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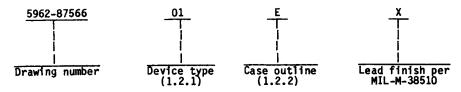
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1.1 Scope. This drawing describes device requirements for class B microcircuits in accordance with 1.2.1 of MIL-STD-883, "Provisions for the use of MIL-STD-883 in conjunction with compliant non-JAN devices".

1.2 Part number. The complete part number shall be as shown in the following example:



1.2.1 Device type. The device type shall identify the circuit function as follows:

 Device type
 Generic number
 Circuit function

 01
 10H558
 Quad, two-input, noninverting multiplexer

1.2.2 Case outlines. The case outlines shall be as designated in appendix C of MIL-M-38510, and as follows:

 Outline letter
 Case outline

 E
 D-2 (16-lead, 1/4" x 7/8"), dual-in-line package

 F
 F-5 (16-lead, 1/4" x 3/8"), flat package

 2
 C-2 (20-terminal, .350" x .350"), square chip carrier package

1.3 Absolute maximum ratings.

1.4 Recommended operating conditions.

When a thermal resistance for this case is specified in MIL-M-38510, appendix C, that value shall supersede the value specified herein.

MILITARY DRAWING
DEFENSE ELECTRONICS SUPPLY CENTER
DAYTON, OHIO

SIZE
A

CODE IDENT. NO.
DWG NO.
5962-87566

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## 2. APPLICABLE DOCUMENTS

2.1 Government specification and standard. Unless otherwise specified, the following specification and standard, of the issue listed in that issue of the Department of Defense Index of Specifications and Standards specified in the solicitation, form a part of this drawing to the extent specified herein.

**SPECIFICATION** 

MILITARY

MIL-M-38510

Microcircuits, General Specification for.

STANDARD

MILITARY

MIL-STD-883

Test Methods and Procedures for Microelectronics.

(Copies of the specification and standard required by manufacturers in connection with specific acquisition functions should be obtained from the contracting activity or as directed by the contracting activity.)

- 2.2 Order of precedence. In the event of a conflict between the text of this drawing and the references cited herein, the text of this drawing shall take precedence.
  - 3. REQUIREMENTS
- 3.1 Item requirements. The individual item requirements shall be in accordance with 1.2.1 of MIL-STD-883, "Provisions for the use of MIL-STD-883 in conjunction with compliant non-JAN devices" and as specified herein.
- 3.2 Design, construction, and physical dimensions. The design, construction, and physical dimensions shall be as specified in MIL-M-38510 and herein.
  - 3.2.1 Terminal connections. The terminal connections shall be as specified on figure 1.
  - 3.2.2 Truth table. The truth table shall be as specified on figure 2.
  - 3.2.3 Logic diagram. The logic diagram shall be as specified on figure 3.
  - 3.2.4 Case outlines. The case outlines shall be in accordance with 1.2.2 herein.
- 3.3 Electrical performance characteristics. Unless otherwise specified, the electrical performance characteristics are as specified in table I and apply over the full recommended ambient operating temperature range.
- 3.4 Marking. Marking shall be in accordance with MIL-STD-883 (see 3.1 herein). The part shall be marked with the part number listed in 1.2 herein. In addition, the manufacturer's part number may also be marked as listed in 6.4 herein.
- 3.5 Certificate of compliance. A certificate of compliance shall be required from a manufacturer in order to be listed as an approved source of supply in 6.4. The certificate of compliance submitted to DESC-ECS prior to listing as an approved source of supply shall state that the manufacturer's product meets the requirements of MIL-STD-883 (see 3.1 herein) and the requirements herein.
- 3.6 Certificate of conformance. A certificate of conformance as required in MIL-STD-883 (see 3.1 herein) shall be provided with each lot of microcircuits delivered to this drawing.
- 3.7 Notification of change. Notification of change to DESC-ECS shall be required in accordance with MIL-STD-883 (see 3.1 herein).

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Test	Symbol	 	Conditions	Group A	Limits		Unit		
	<u> </u>	unless	< TA < +125°C otherwise specif	ied	subgroups	Min	Max	<u> </u>	
Cases E, F, and 2	1	Quies	cent conditions	1/ VIL	<del></del>		<del></del>		
High level output voltage	V <sub>OH</sub>	  Outputs  terminated  through  1000 to -2	-0.780    -0.650    -0.840	-1.950 -1.950	2	  -1.010  -0.860  -1.060	-0.650	1	
Low level output voltage	V <sub>OL</sub>	V <sub>CC</sub> = 0.0 V V <sub>EE</sub> = -5.2 V	$V_{CC} = 0.0 \text{ V}$	V 1-0.780 I	-1.950		-1.950 -1.950 -1.950		j
High level threshold output voltage	V <sub>OHA</sub>	  -  -	-1.110    -0.960    -1.160	-1.465		-1.010 -0.860 -1.060		1	
Low level threshold output voltage	I V <sub>OLA</sub>	 	-1.110  -0.960  -1.160	-1.465		-1.950  -1.950  -1.950		1	
Power supply drain current	I <sub>EE</sub>	 			1 2, 3	-48   -53\	 	mA	
High level input current	IIH1	 	   Select 	;	1, 2		295 475	μА	
	I <sub>IH2</sub>	  Outputs  terminated	All fr	puts	1, 2	 	320 515	] ] μΑ	
Low level input current	IIL	100Ω to -2  V <sub>EE</sub> = -5.2  V <sub>CC</sub> = 0.0 V  All inputs	V 1 1		1, 3	 	0.5	Ι ! μΑ ! μΑ	
Cases E and F		DC rapid	test conditions	2/			<i></i>	<u></u>	
High level output voltage	   V <sub>ОН</sub> 	  Outputs  terminated  through  1000 to -2	VIH  -0.793    -0.665    -0.855	-1.950	2	    -1.022  -0.874  -1.074	-0.665	ĺ	
Low level output voltage	V <sub>OL</sub>	V <sub>CC</sub> = 0.0 V V <sub>EE</sub> = -5.2	V  -0.793    -0.665    -0.855	-1.950	2	-1.950 -1.950 -1.950	1-1.570	1	
MILITARY DRAV		SIZE	CODE IDENT. N. 67268	O. DW	G NO.				
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Test	Symbol	Cond	itions A < +125°C		Group A	Limits		Unit
	<u> </u>	-55°C < T unless othe	A < +125°C rwTse speci	fied	subgroups	Min	Max	<u> </u> 
Cases E and F	T	DC rapid tes	t condition	s 2/	<del></del>			<del></del>
High level threshold output voltage	V <sub>OHA</sub>	  Outputs  terminated  through  1000 to -2V	1	  -1.484  -1.470	1 2	-1.022 -0.874 -1.074	-0.665	1
Low level threshold output voltage	I V <sub>OLA</sub>	TV <sub>CC</sub> = 0.0 V  V <sub>EE</sub> = -5.2 V	-1.122  -0.974  -1.174	-1.470	1 1 2 1 3	-1.950 -1.950 -1.950	-1.570	ĺ
Power supply drain current	IEE				1 2, 3	-47 -52		mA
High level input current	I <sub>IH1</sub>		   Selec	Select			280 460	   μΑ
	I <sub>IH2</sub>	  Outputs  Iterminated	terminated				305 500	   μΑ
Low level input current	IIL	1000 to -2 V  YEE = -5.2 V  YCC = 0.0 V  All inputs	1	]   	1, 3		0.5	   μΑ   μΑ
Case 2		DC rapid tes	t condition	s 2/	<del></del>		· · · · · · · · · · · · · · · · · · ·	
High level output voltage	V <sub>ОН</sub>	   iOutputs  terminated  through  1000 to -2 V	V <sub>IH</sub>  -0.800  -0.671  -0.861		   1   2   3	-1.028  -0.880  -1.080	-0.671	ļ .
Low level output voltage	YoL	Y <sub>CC</sub> = 0.0 V   Y <sub>EE</sub> = -5.2 V	-0.800  -0.671  -0.861	-1.950  -1.950	1 2	-1.950 -1.950 -1.950	-1.572	1
High level threshold output voltage	V <sub>OHA</sub>		-1.128  -0.980  -1.180	1-1.472	1   2   3	-1.028 -0.880 -1.080	-0.671	1
Low level threshold output voltage	V <sub>OLA</sub>		-1.128  -0.980  -1.180	-1.472	2	-1.950 -1.950 -1.950	-1.572	!
Power supply drain current	IEE		]		1 2, 3	-47   -52		l mA
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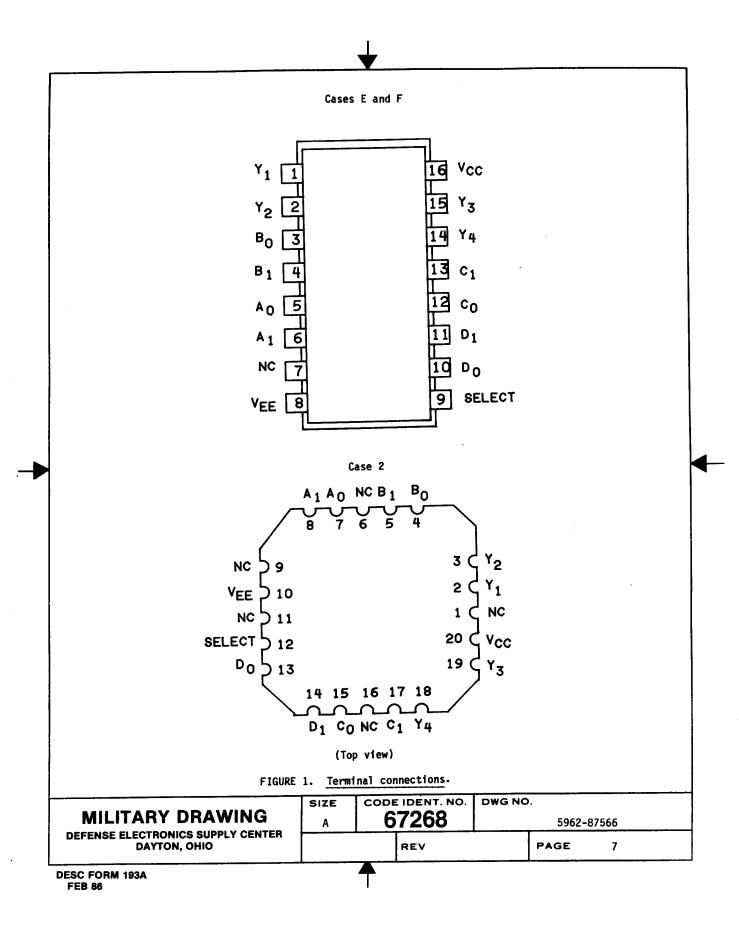
Test	Symbol	Condition	Group A	<u>Lim</u>	Unit		
	<u> </u>	-55°C < TA < unless otherwi	+125 C se specified	subgroups	Min	Max	<u> </u>
Case 2		DC rapid test co	onditions 2/				
High level input current	IIHI		Select	1, 2		280 460	μ.
	I <sub>IH2</sub>	  Outputs  terminated	   All inputs 	1, 2		305 500	   μ
Low level input current	IIL	100Ω to -2 V  V <sub>EE</sub> = -5.2 V  V <sub>CC</sub> = 0.0 V  A11 inputs	 	1, 3	·	0.5	   μ.   μ.
Cases E, F, and 2		AC test conditi	ons				
Transition time	tTLH tTHL t+, t-	V <sub>EE</sub> = -2.94 V <sub>CC</sub> = 2.0 V C <sub>L</sub> < 5 pF		9 10 11	0.70 0.70 0.70	2.00 2.20 2.20	n:
Propagation delay time	tpHH1 tpLL1 tpHL1 tpHH1	Load all outputs   100Ω to ground       	through	9   10   11	0.50 0.50 0.50	1 1.80   2.20   1.90	   n:     
Propagation delay time	tpHH2 tpLL2 tpHL2 tpHL2 tpHL2	-    -  -		9 10 11	1.00 1.00 1.00	2.70 3.00 2.70	l ns

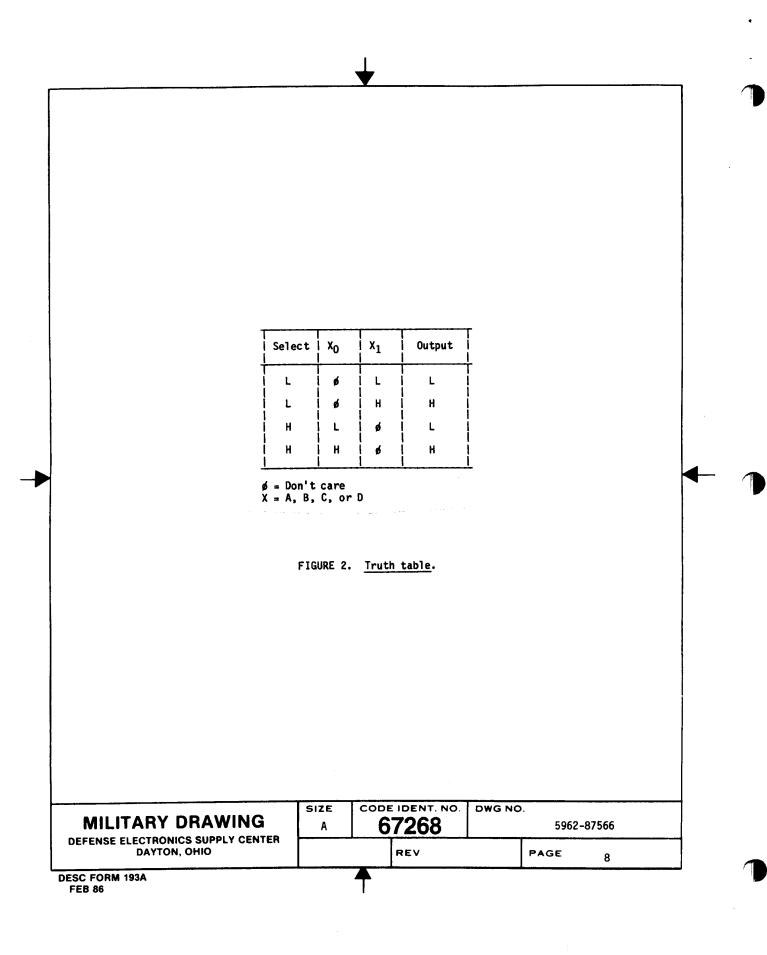
<sup>1/</sup> The quiescent limits are determined after a device has reached thermal equilibrium. This is defined as the reading taken with the device in a socket with  $\geq 500$  LFPM of  $\pm 25$ °C air blowing on the unit and with power applied at least four minutes before the reading is taken.

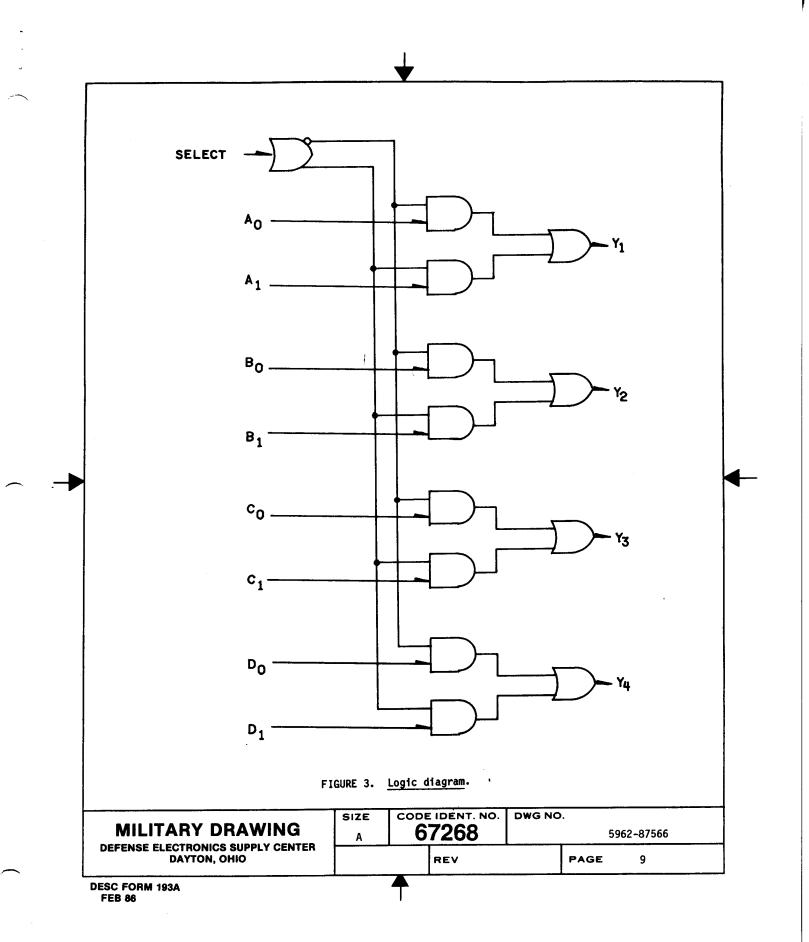
MILITARY DRAWING DEFENSE ELECTRONICS SUPPLY CENTER DAYTON, OHIO	SIZE	67268	DWG NO. 5962-87566		
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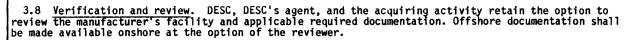
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<sup>2/</sup> The dc rapid test forcing functions and limits are used for all dc testing. These limits are determined for each device type based on the power dissipation and package type. The rapid test (delta V) limits and forcing functions are skewed allowing rapid testing to be performed at standard temperatures without the addition of delta T's.









- 4. QUALITY ASSURANCE PROVISIONS
- 4.1 Sampling and inspection. Sampling and inspection procedures shall be in accordance with section 4 of MIL-M-38510 to the extent specified in MIL-STD-883 (see 3.1 herein).
- 4.2 Screening. Screening shall be in accordance with method 5004 of MIL-STD-883, and shall be conducted on all devices prior to quality conformance inspection. The following additional criteria shall apply:
  - a. Burn-in test (method 1015 of MIL-STD-883).
    - (1) Test condition A, B, C or D using the circuit submitted with the certificate of compliance (see 3.5 herein).
    - (2)  $T_A = +125^{\circ}C$ , minimum.
  - b. Interim and final electrical test parameters shall be as specified in table II herein, except interim electrical parameter tests prior to burn-in are optional at the discretion of the manufacturer.
- 4.3 Quality conformance inspection. Quality conformance inspection shall be in accordance with method 5005 of MIL-STD-883 including groups A, B, C, and D inspections. The following additional criteria shall apply.
  - 4.3.1 Group A inspection.
    - a. Tests shall be as specified in table II herein.
    - b. Subgroups 4, 5, 6, and 8 in table I, method 5005 of MIL-STD-883 shall be omitted.
    - c. Subgroup 4 ( $C_{\rm IN}$  measurement) shall be measured only for the initial test and after process or design changes which may affect input capacitance.
    - d. Subgroup 7 test shall verify the truth table.
  - 4.3.2 Groups C and D inspections.
    - a. End-point electrical parameters shall be as specified in table II herein.
    - b. Steady-state life test (method 1005 of MIL-STD-883) conditions:
      - (1) Test condition D using the circuit submitted with the certificate of compliance (see 3.5 herein).
      - (2)  $T_A = +125^{\circ}C$ , minimum.
      - (3) Test duration: 1,000 hours, except as permitted by appendix B of MIL-M-38510 and method 1005 of MIL-STD-883.

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## TABLE II. Electrical test requirements.

MIL-STD-883 test requirements	Subgroups     (per method   5005, table I)
  Interim electrical parameters   (method 5004)	1 
  Final electrical test parameters   (method 5004)	1*,2,3,7*,9
  Group A test requirements   (method 5005)	1,2,3,7,9,10, 11
  Groups C and D end-point   electrical parameters   (method 5005)	1,2,3

<sup>\*</sup> PDA applies to subgroups 1 and 7.

- 5. PACKAGING
- 5.1 Packaging requirements. The requirements for packaging shall be in accordance with MIL-M-38510.
- 6. NOTES
- 6.1 Intended use. Microcircuits conforming to this drawing are intended for use when military specifications do not exist and qualified military devices that will perform the required function are not available for OEM application. When a military specification exists and the product covered by this drawing has been qualified for listing on QPL-38510, the device specified herein will be inactivated and will not be used for new design. The QPL-38510 product shall be the preferred item for all applications.
- 6.2 Replaceability. Microcircuits covered by this drawing will replace the same generic device covered by a contractor-prepared specification or drawing.
- 6.3 Comments. Comments on this drawing should be directed to DESC-ECS, Dayton, Ohio 45444, or telephone 513-296-5375.

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6.4 Approved source of supply. An approved source of supply is listed herein. Additional sources will be added as they become available. The vendor listed herein has agreed to this drawing and a certificate of compliance (see 3.5 herein) has been submitted to DESC-ECS.

Military drawing part number	Vendor   CAGE   number	Vendor 1/ similar part number
5962-8756601EX	04713	10H558/BEAJC
5962-8756601FX	04713	10H558/BFAJC
5962-87566012X	04713	10H558M/B2CJC

1/ Caution. Do not use this number for item acquisition. Items acquired to this number may not satisfy the performance requirements of this drawing.

Vendor CAGE number

04713

Vendor name and address

Motorola, Incorporated 7402 South Price Road Tempe, AZ 85283

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